
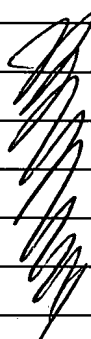


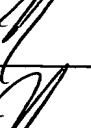

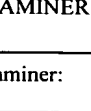
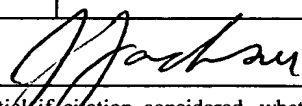


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| INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) | | | | APPLICANT Mitsutoshi MIYASAKA | | FILING DATE June 21, 2001 | |
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